Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/618,944	CHEN, CHIH-WEI
Examiner	Art Unit
Andrew Setlak	2166

	SEARCHED		
Class	Subclass	Date	Examiner
707	200,204	3/6/2006	AS
711	114	3/6/2006	AS

INT	ERFERENC	ENCE SEARCHED	
Class	Subclass	Date	Examiner
	 		
	<u> </u>		

SE (INCLUDING	ARCH NOTES SEARCH STRAT	EGY)
	DAT	
East	3/6/20	006 AS
Google	2/3/20	006 AS